

# Search Notes



Application/Control No.

10/633,595

Examiner

Patrick J. Lee

Applicant(s)/Patent under  
Reexamination

OIKAWA ET AL.

Art Unit

2878

## SEARCHED

Class	Subclass	Date	Examiner
250	221, 222.1, 234, 235	2/14/2005 2/15/2005	PL
340	555-557	2/16/2005	PL
355	55-56	2/16/2005	PL
355	67-68	2/16/2005	PL

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Consulted w/ S. Allen	2/14/2005	PL
East (see attached)	2/14/2005	PL
East (see attached)	2/15/2005	PL
East (see attached)	2/16/2005	PL